Save Time **Save Expense** **Improve Yields**

Semiconductor fabs and OEMs worldwide value the accuracy, precision and versatility of WaferSense – The most efficient and effective wireless measurement device for wafer handoff teaching.

WS

WaferSense® SDK

Software Development Kit

WaferSense SDK

The WaferSense Software Development Kit provides the Application Programming Interface (API) to the WaferSense® and ReticleSense® family of devices. This allows direct integration of the device into user developed software applications.

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WaferSense® SDK Software Development Kit

Programming Language
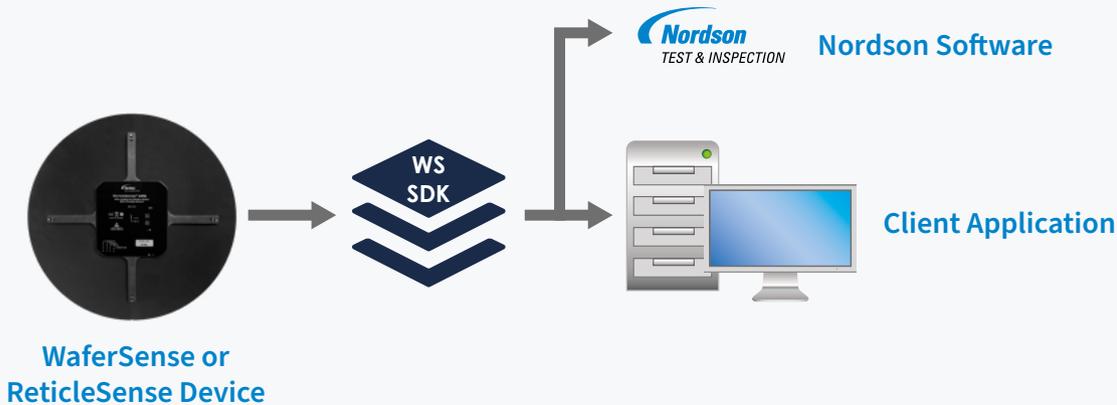
Programming language and development environment support:

- WaferSense API

  .net framework 4.6.1 for Windows 64 bit

  Java version for both Windows & Linux 64 bit

What's Included

The WaferSense SDK Includes:

- WaferSense library
- Programmers Guide
- Installers .net/.jar and Link Box Drivers
- Sample code

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WS SDK

Client Application

WaferSense or ReticleSense Device

WaferSense SDK Features	
Required device	Only WaferSense or ReticleSense devices setup as SDK devices can be accessed with the WaferSense SDK libraries. The device will be connected to the user's computer using the Nordson WaferSense Link Box.
OS platform	Windows 64 bit / Linux 64 bit
Programming language and development environment support	.net framework 4.6.1 or JDK > Version 11
Software features	Start and stop measurements. All data sent back via .net/Java events. Diagnostic messages can be configured and returned to user via .net/Java event. Exceptions used to report errors to user.

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